

2

HDL TM-91-11

AD-A239 558

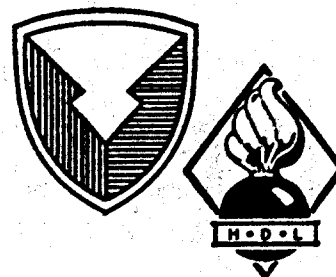


August 1991

**Electron-Beam-Pinch Experiment at Harry Diamond
Laboratories: Providing for a High-Dose-Rate Flash
X-Ray Facility for Transient Radiation Effects on
Electronics (TREE) Testing of Pieceparts**

by Dale N. Robertson
Marc S. Litz
Steven M. Blomquist
James C. Blackburn
Gregory K. Ovrebo

DTIC
ELECTE
AUG 20 1991
S B D



U.S. Army Laboratory Command
Harry Diamond Laboratories
Adelphi, MD 20783-1197

Approved for public release; distribution unlimited.

91 8 19 036

91-08159



The findings in this report are not to be construed as an official Department of the Army position unless so designated by other authorized documents.

Citation of manufacturer's or trade names does not constitute an official endorsement or approval of the use thereof.

Destroy this report when it is no longer needed. Do not return it to the originator.

REPORT DOCUMENTATION PAGE			Form Approved OMB No. 0704-0188	
Public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0188), Washington, DC 20503.				
1. AGENCY USE ONLY (Leave blank)		2. REPORT DATE August 1991		3. REPORT TYPE AND DATES COVERED Final, May 1990-July 1990
4. TITLE AND SUBTITLE Electron-Beam-Pinch Experiment at Harry Diamond Laboratories: Providing for a High-Dose-Rate Flash X-Ray Facility for Transient Radiation Effects on Electronics (TREE) Testing of Pieceparts				5. FUNDING NUMBERS PE: 62120
6. AUTHOR(S) Dale N. Robertson, Marc S. Litz, Steven M. Blomquist, James C. Blackburn, and Gregory K. Ovrebo				
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Harry Diamond Laboratories 2800 Powder Mill Road Adelphi, MD 20783-1197				8. PERFORMING ORGANIZATION REPORT NUMBER HDL-TM-91-11
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES) USA Strategic Defense Command PO Box 1500 Huntsville, AL 38508				10. SPONSORING/MONITORING AGENCY REPORT NUMBER
11. SUPPLEMENTARY NOTES AMS code: 612120.H2500 HDL PR: 274028				
12a. DISTRIBUTION/AVAILABILITY STATEMENT Approved for public release; distribution unlimited.				12b. DISTRIBUTION CODE
13. ABSTRACT (Maximum 200 words) The peak photon-radiation dose rate of the Harry Diamond Laboratories (HDL) High-Intensity Flash X-Ray facility has been increased by at least a factor of five through the use of custom beam-pinch hardware. With this hardware, the facility can now routinely provide a dose rate of 2.7×10^{11} rads(Si)/s, at a distance of 1/4 in. from the drift-tube face, while providing excellent radial drop-off to minimize irradiation of items surrounding the device under test. The experimental results show the optimum operating parameters of the beam-pinch hardware to be a drift-tube length equal to 6 cm with an internal nitrogen gas pressure of 0.1 Torr.				
14. SUBJECT TERMS Flash x-ray, electron beam, Bremsstrahlung, dose rate, photons, radiation simulation				15. NUMBER OF PAGES 15
				16. PRICE CODE
17. SECURITY CLASSIFICATION OF REPORT Unclassified	18. SECURITY CLASSIFICATION OF THIS PAGE Unclassified	17. SECURITY CLASSIFICATION OF ABSTRACT Unclassified	20. LIMITATION OF ABSTRACT UL	

Contents

	Page
1. Introduction	5
2. Approach	5
3. Theory	5
4. Experimental Design	6
5. Experimental Procedure	7
6. Results	7
7. Conclusions	12

Figures

1. Diagram of movable target drift-tube assembly	6
2. HIFX beam pinch at 0.05 Torr, ¼ in. from face	8
3. HIFX beam pinch at 0.1 Torr, ¼ in. from face	8
4. HIFX beam pinch at 0.25 Torr, ¼ in. from face	9
5. HIFX beam pinch at 0.5 Torr, ¼ in. from face	9
6. HIFX beam pinch at ¾ in. from face, showing drift-tube length	10
7. HIFX beam pinch at ¾ in. from face, showing pressure	11
8. HIFX beam pinch. Ratio of dose rate at ¼ in. to dose rate at ¾ in.	11
9. HIFX beam pinch (tube length, 6 cm; pressure, 0.1 Torr)	12



Accession For	
NTIS GRA&I	☒
DTIC TAB	☐
Unannounced	☐
Justification	
By _____	
Distribution/	
Availability Codes	
Dist	Avail and/or Special
A-1	

1. Introduction

Over the past year, data were taken at Harry Diamond Laboratories (HDL) to measure the response of radiation-hardened semiconductor devices to transient radiation.¹ These tests indicate that for input and tri-stated output photocurrents and some upset measurements, intense ($>1 \times 10^{11}$ rads(Si)/s), small-diameter photon beams are preferred over electron beams. To meet this requirement, we set about to increase the dose rate available at the HDL high-intensity flash x-ray machine (HIFX) through beam focussing; the maximum useful dose rate then available was 5×10^{10} rads(Si)/s. Our approach was to decrease the spot size of the radiation, which provides more intense irradiation of the die, with less irradiation on the associated die package, printed circuit board, and test fixture. By minimizing the radiation outside the die, signals induced by internal electromagnetic pulse (IEMP) on the circuit board would also be minimized.

The goal of these tests was to achieve a $>1 \times 10^{11}$ rads(Si)/s photon beam over about a 1-cm²-diam area with a uniformity of better than 90 percent and a rapid falloff in the radial direction (r). Such a rapid falloff minimizes or eliminates the need for lead shielding of the circuitry near the die. The space needed for shielding forces the device under test to be farther away from the tantalum (Ta) target and consequently it receives less ionizing dose rate.

2. Approach

The approach used was to allow the electron beam to pass through the titanium (Ti) window of the HIFX tank into a drift tube with a partial pressure of nitrogen (N). At the correct gas pressure, a neutral charge region is formed within the drift tube, allowing the self-magnetic field to collapse the electron beam, which causes the beam to focus (or pinch). The pinched beam then strikes a Ta target, producing photons. The optimum gas pressure and drift-tube length were determined experimentally.

3. Theory

Calculations based on single-particle trajectories indicate that a drift-tube length of about 2.5 to 3 times the incoming electron-beam diameter will produce a pinched beam, given the energy of the HIFX

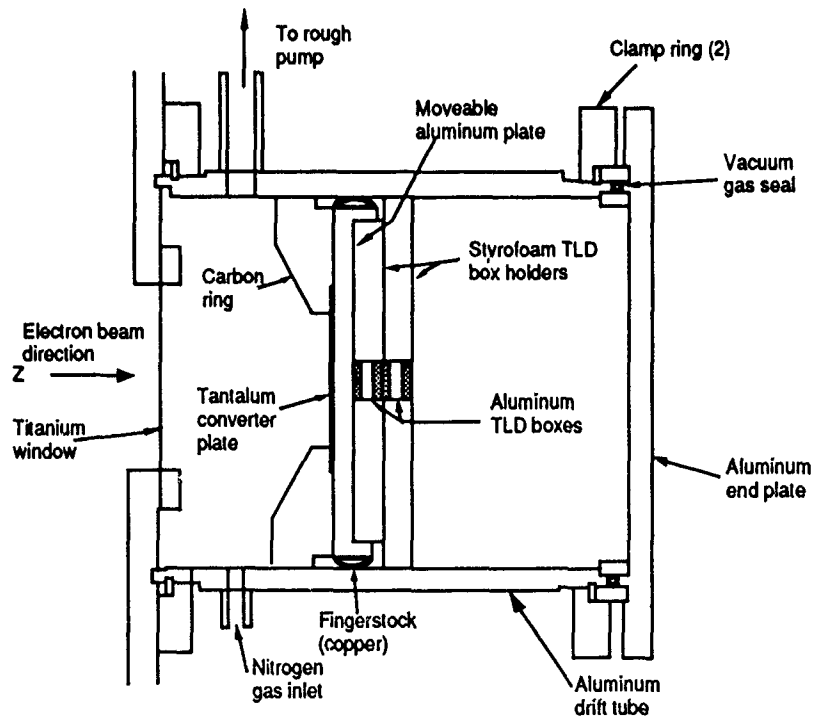
¹C. Self, C. Tipton, S. Murrill, H. Eisen, and G. Brucker (GE/ASD), *Input and Tri-Stated Output Photocurrent in CMOS SRAMs*, Harry Diamond Laboratories, HDL-TM-91-8 (June 1991).

electrons.* These calculations assume that the drift tube is filled with a low-pressure gas which will neutralize the repulsive electric fields of electrons in the beam. With the electric forces minimized, only self-magnetic forces would act on the electrons. This analysis assumes a perfectly charge-neutralized system. The ionization fraction due to the background gas is not easily converted to an absolute pressure, so the optimum pressure must be empirically determined. Nitrogen is a convenient and readily available gas; pressures on the order of 0.1 to 1 Torr are expected to produce a charge-neutralized electron-drift region, given the total current of the HIFX electron beam.²

4. Experimental Design

To determine the most satisfactory pinch conditions, we constructed an apparatus (shown in fig. 1) in which drift-tube length and pressure could be varied. A 20-cm-long aluminum (Al) drift tube with an Al endplate was attached to the faceplate of the HIFX, which was operating in the electron-beam mode (Ti window in place).† A 3/8-in.-

Figure 1. Diagram of movable target drift-tube assembly.



²S. E. Graybill and S. V. Nablo, *Observations of Magnetically Self-Focusing Electron Streams*, *Appl. Phys. Lett.* 8, 1 (January 1966), 18-20.

*W. A. Seidler, *Design Theory for the Pinch*, private communication.

†The electron beam exiting the Ti window is estimated to be 2 to 3 cm in diameter with the standard cone-shaped cathode (this could vary if a different cathode were used); therefore, the optimum drift-tube length is less than 10 cm.

thick movable (in the z direction—that is, normal to the Ti window) Al plate, held in place with rf fingerstock, was located within the drift tube. A 15-mil-thick by 3.0-in.-diam Ta converter plate was located in front of the movable plate. The converter was surrounded and held in place by a 1-in.-thick carbon (C) ring and shaped to roughly maintain the impedance seen by the electron beam as its diameter narrowed to the pinch. The outer perimeter of the converter was attached to the C ring with copper tape.

Thermoluminescent dosimeters (TLDs)* and a coaxial x-ray diode (CXRD) were placed in the drift tube beyond the movable plate to measure total dose and time history. The movable plate, Ta converter, TLDs, and CXRD all moved as a unit, so their relative locations remained unchanged as the drift length was varied. The drift tube was pumped down to 0.01 Torr using a roughing pump. With the pump running, N was continuously flowed through the drift tube at a rate to maintain the desired pressure level.

5. Experimental Procedure

In these experiments, the HIFX was charged to 4.1 MV, providing a photon spectral peak of 400 keV. This charging voltage is optimum for minimizing tank sparks and hence maximizing the mean time between machine failures, while providing substantial electron-beam current—about 25 kA.

For the first series of shots, the movable target was set at drift-tube lengths of 5, 6, 7, and 8 cm. For each length, shots were performed at drift-tube pressures of 0.05, 0.1, 0.25, and 0.5 Torr. Multiple shots were generally taken at each condition.

Two TLDs were used for each shot. They were held in TLD pillboxes, placed along the drift-tube central axis behind the movable aluminum plate, by mounting the pillboxes in styrofoam disks. The pillboxes are about $\frac{7}{16}$ in. thick and were centered in styrofoam pillbox holders about $\frac{1}{2}$ in. thick. Hence, the TLDs themselves were located about $\frac{1}{4}$ and $\frac{3}{4}$ in. from the movable plate (see fig. 1).

6. Results

Figures 2 through 5 are plots of dose rate vs drift-tube length for pressures of 0.05, 0.1, 0.25, and 0.5 Torr, respectively, for the TLD located $\frac{1}{4}$ in. from the movable plate. In the pinched-beam mode, the

*We used standard HIFX calcium fluoride (CaF_2) TLDs in Al pillboxes for electronic equilibrium.

Figure 2. HIFX beam pinch at 0.05 Torr, 1/4 in. from face.

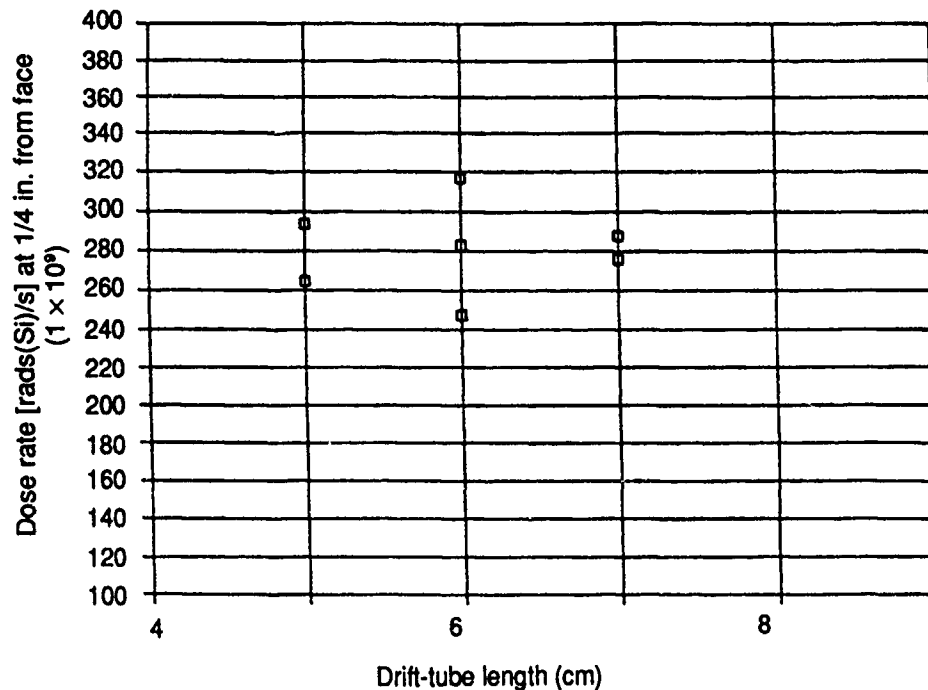
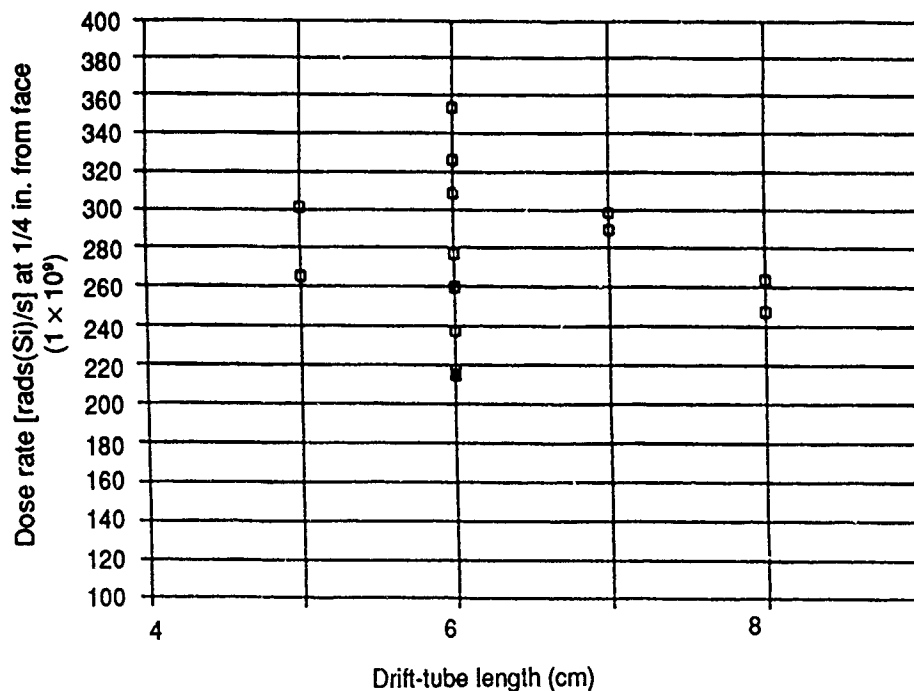


Figure 3. HIFX beam pinch at 0.1 Torr, 1/4 in. from face.



pulse width narrowed from 25-ns FWHM to 18-ns FWHM with a risetime of about 8 ns (as measured by the CXRD). In figures 4 and 5 it is not possible to determine with confidence the tube length corresponding to peak dose rate, but it appears reasonable to assume by linear extrapolation that the peak dose rate will not be any larger than the peak value seen in figure 3, at 0.1 Torr. At this pressure (0.1 Torr),

Figure 4. HIFX beam pinch at 0.25 Torr, 1/4 in. from face.

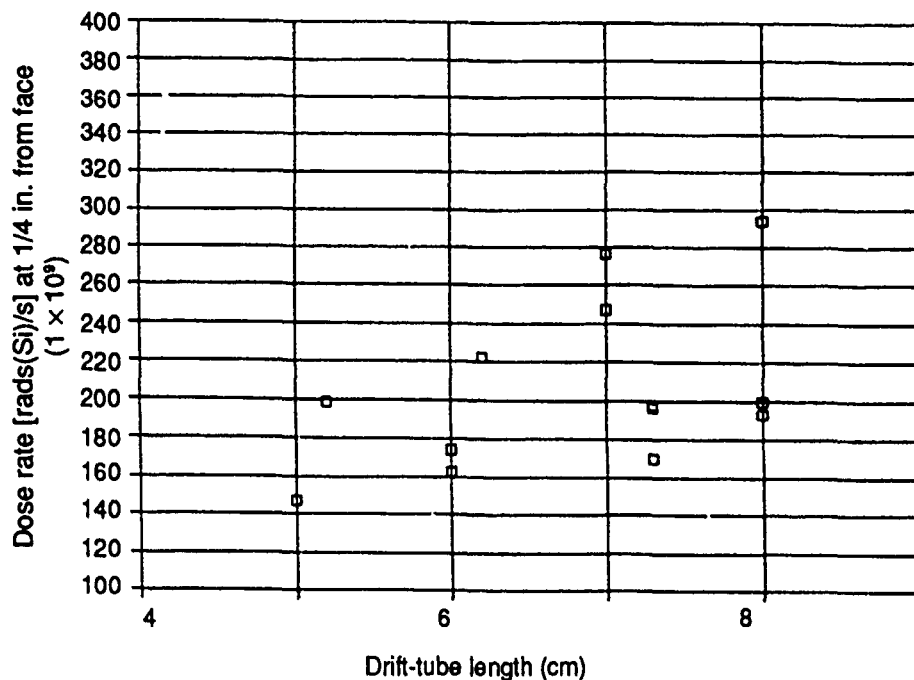
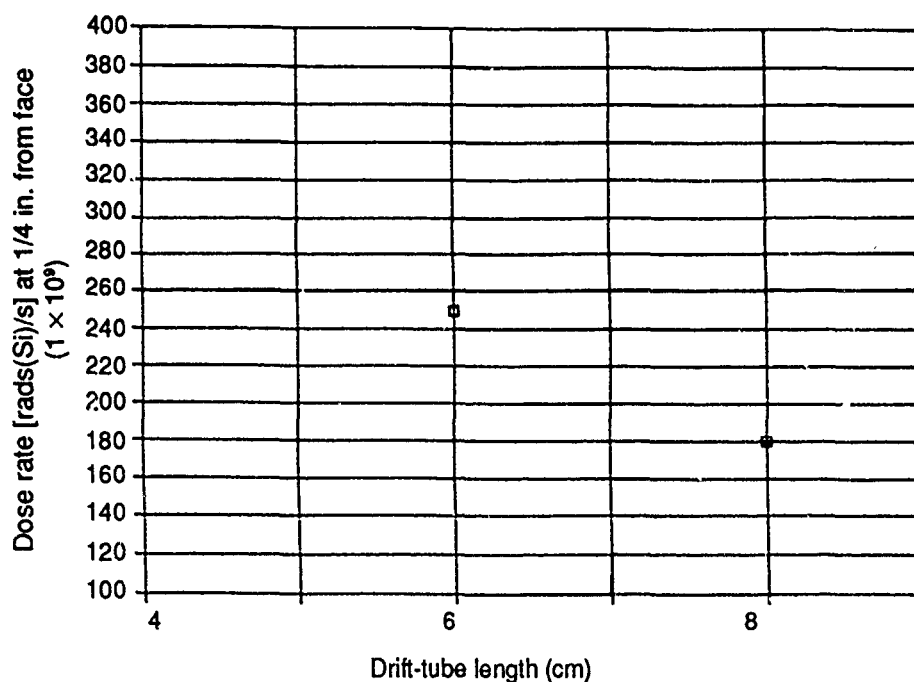


Figure 5. HIFX beam pinch at 0.5 Torr, 1/4 in. from face.



maximum dose rate was achieved with a drift-tube length of 6 cm. In figure 3, we see that the eight shots ranged from 2.1×10^{11} to 3.5×10^{11} , with a mean and median of about 2.7×10^{11} rads(Si)/s. HIFX in the normal photon mode averages about 5×10^{10} rads(Si)/s. Thus, it appears that even this simple beam-pinch system increases the dose rate roughly by a factor of 5 and provides a faster risetime—8 ns.

Figures 6 and 7 show results at the second TLD location ($\frac{3}{4}$ in. from Al plate). Figure 6 combines all pressures used with drift-tube length as the independent variable, and figure 7 combines all lengths with pressure as the independent variable. These data indicate that a 6-cm-long tube at a pressure of 0.1 Torr is optimum. When evaluating the readings of these second TLDs, one needs to consider the shadowing effects of the first TLD pillbox on the second TLD. Based on a simple calculation, we estimate that the reported values of the second TLDs should be increased by at least 10 percent.

In figure 8, the ratio of the first TLD reading to the second TLD reading is plotted versus the dose rate of the first TLD. High dose rates at the first TLD mean good beam pinches; i.e., the photons are concentrated at the location of the first TLD. It was anticipated that a good beam pinch would result in more beam divergence and consequently a more rapid drop-off in the z direction, resulting in a higher ratio of the first TLD reading to the second reading. Figure 8 confirms this conclusion.

After the first series of shots, a shot was taken with a 6-cm drift-tube length and 0.1-Torr pressure, using an array of TLDs five wide (r direction) and three deep (z direction).

Figure 9 shows the radial drop-off in dose rate for three distances from the movable plate: $\frac{1}{4}$, $\frac{3}{4}$, and $1\frac{1}{4}$ in. As the modest peak dose rate at $\frac{1}{4}$ in. (2.0×10^{11} rads(Si)/s) indicates, this shot was not one of the better pinches. Even so, the radial drop-off at $z = \frac{1}{4}$ in. is significant, with the

Figure 6. HIFX beam pinch at $\frac{3}{4}$ in. from face, showing drift-tube length.

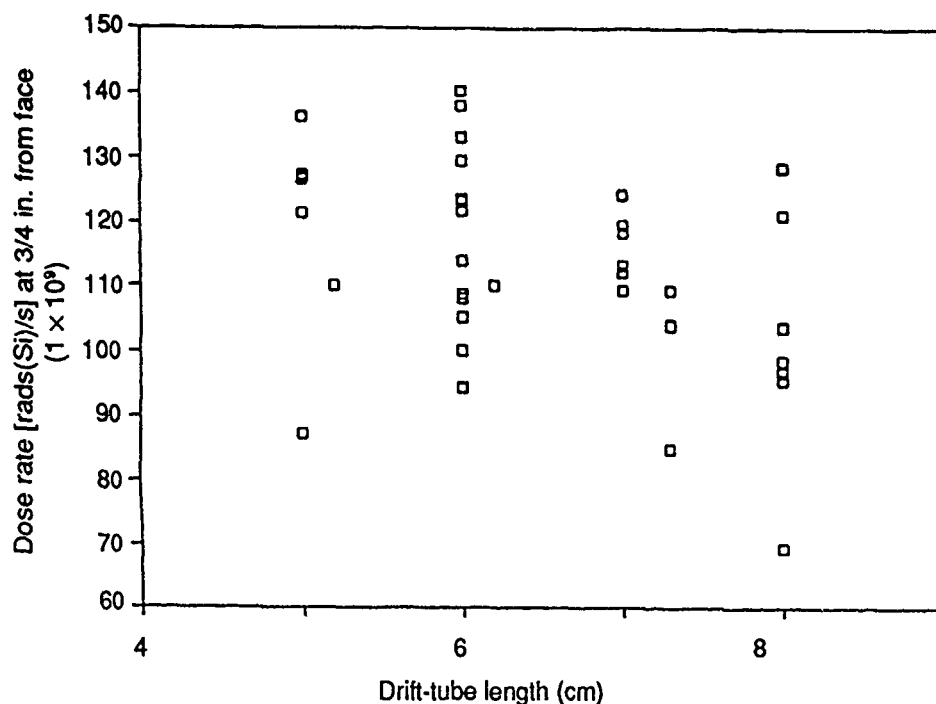


Figure 7. HIFX beam pinch at $\frac{3}{4}$ in. from face, showing pressure.

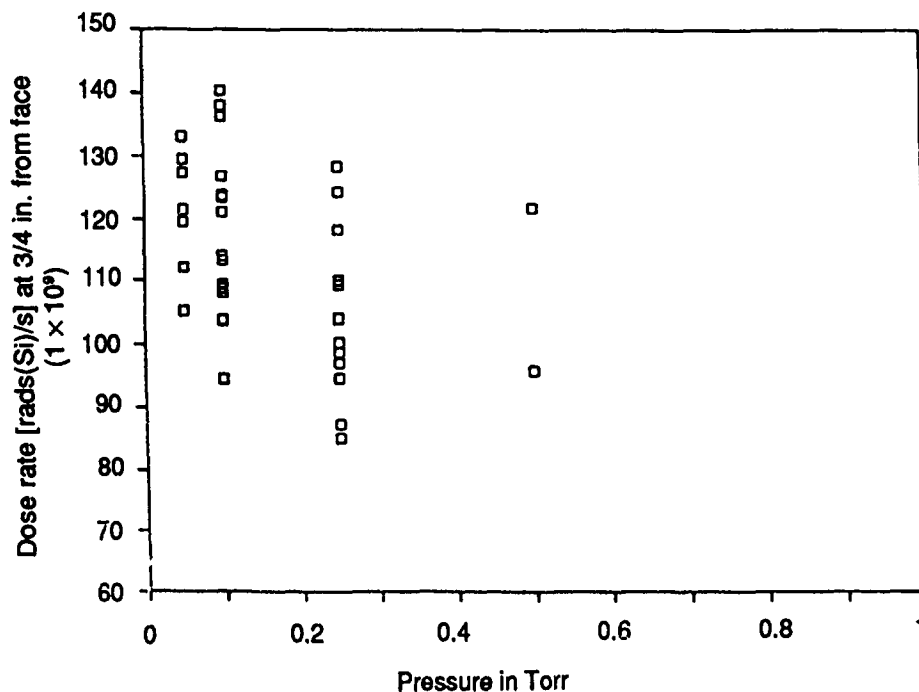
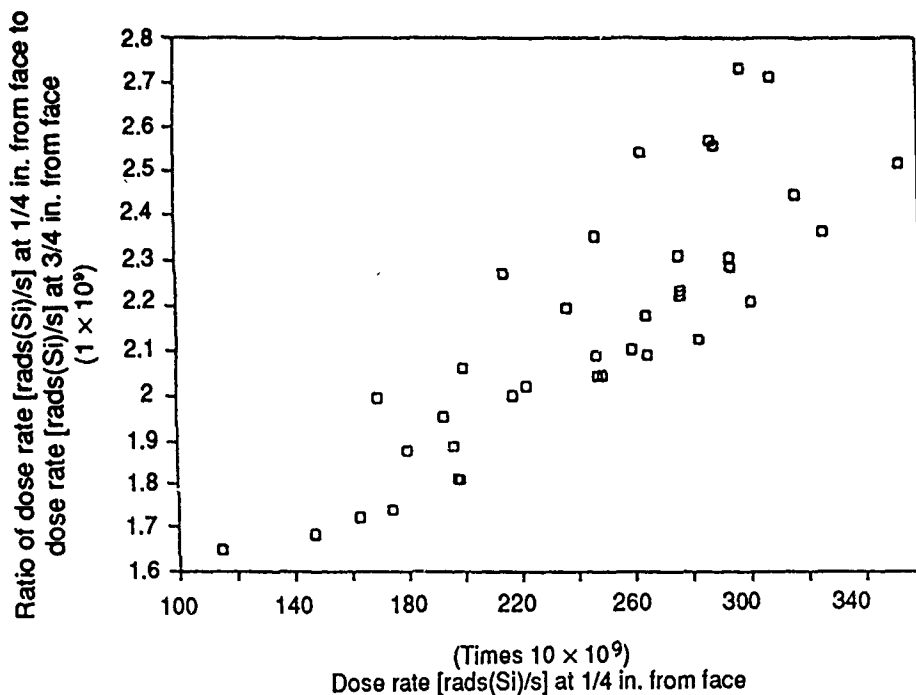
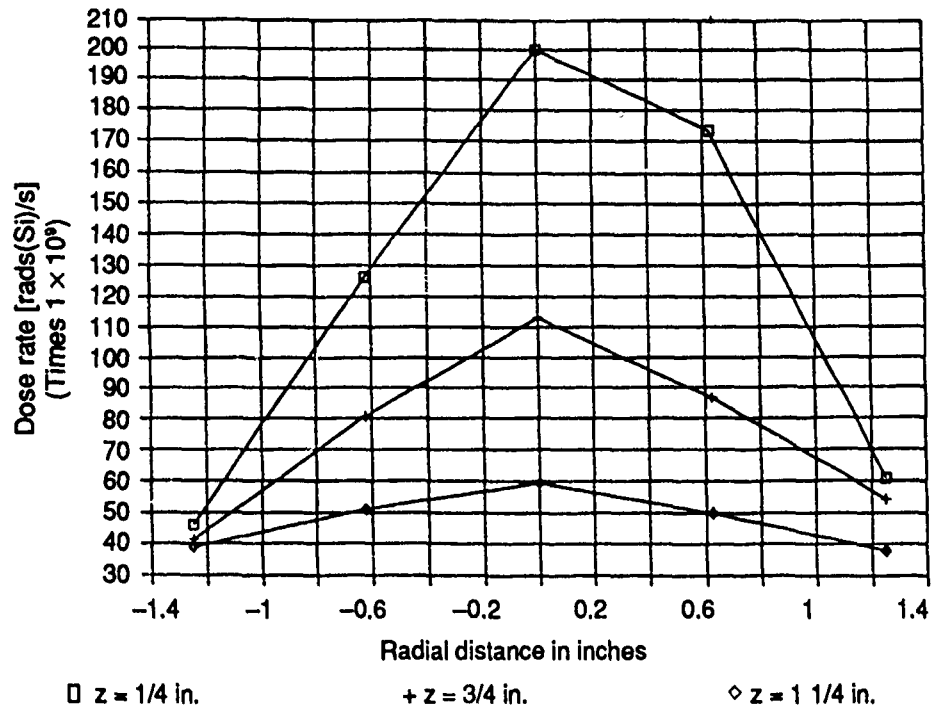


Figure 8. HIFX beam pinch. Ratio of dose rate at $\frac{1}{4}$ in. from face to dose rate at $\frac{3}{4}$ in.



radiation down by a factor of 2 to 2.5 at $r = 1$ in. and down by about a factor of 4 at $r = 1.25$ in. Even more rapid drop-off would be expected with better pinches which more closely approximate a point source.

Figure 9. HIFX beam pinch (tube length, 6 cm; pressure, 0.1 Torr).



7. Conclusions

The peak photon-radiation dose rate of the HDL HIFX facility has been increased by at least a factor of 5 through the use of custom, beam-pinching hardware. With this hardware, the facility can now routinely provide a dose rate of 2.7×10^{11} rads(Si)/s, at a distance of $1/4$ in. from the drift-tube face, while providing excellent radial drop-off to minimize irradiation of items surrounding the device under test. Even at a distance of $3/4$ in. from the face, the facility can now routinely provide a dose rate $>1 \times 10^{11}$ rads(Si)/s. The experimental results show the optimum operating parameters of the beam-pinching hardware to be a drift-tube length equal to 6 cm with an internal N gas pressure of 0.1 Torr.

Distribution

Administrator
Defense Technical Information Center
Attn DTIC-DDA (2 copies)
Cameron Station, Building 5
Alexandria, VA 22304-6145

Defense Nuclear Agency
Attn RAEE, G. Davis
Attn RAEE, LCDR L. Cohn
6801 Telegraph Road
Alexandria, VA 22310-3398

SDIO
Department of Defense
Attn LTC C. Hill
Washington, DC 20301-7100

US Army Corps of Engineers
Attn CEHND-ED-SY, J. Loyd
PO Box 1600, 106 Wynn Drive
Huntsville, AL 35807-3701

Director
US Army Strategic Defense Command
Attn CSSD-H-SAV, G. Pollock
Attn CSSD-H-SAV, L. Ziegler
Attn CSSD-H-SAV, P. Simpson
Attn CSSD-H-SAV, R. Bradshaw
Attn CSSD-H-SAV, R. Crowson
Attn CSSD-H-LS, D. Lambert
Attn CSSD-H-LS, I. Merritt
Attn CSSD-H-YA, D. Stott
Attn CSSD-H-YA, C. Harper
Attn CSSD-KE-T, G. Sanders
Attn CSSD-KE-T, D. Bouska
PO Box 1500
Huntsville, AL 35807

Director
National Security Agency
Attn Y253, J. Hilton
FT George G. Meade, MD 20755

Allen Research
Attn B. Seidler

Allen Research (cont'd)
Attn M. Salazar
4950 Corporate Drive
Huntsville, AL 35805-6221

Harris Corporation
Attn A. Sanchez, MS19
Attn G. Chunn, MS19
Attn P. Austin, MS 19
Attn R. Kronebusch, MS20
Attn W. E. Abare, MS 20
PO Box 94000
Melbourne, FL 32901

Jaycor
Attn C. McKnett
Attn C. Rogers
Attn R. Poll
2951 28th St., Suite 3075
Santa Monica, CA 90405-2993

Jaycor
Attn B. Passenheim
Attn C. Mallon
Attn D. Bruener
Attn D. Walters
Attn E. Wenaas
Attn H. Harper
Attn J. Weidler
Attn R. Leadon
Attn R. Stahl
Attn S. Lutjens
Attn T. Ash
Attn T. Flanagan
PO Box 85154
San Diego, CA 92138-9259

K-Tech
Attn T. Smith
901 Pennsylvania Ave, N.E.
Albuquerque, NM 87110

Kaman Sciences
Attn J. Tinsley

Distribution (cont'd)

Kaman Sciences (cont'd)
Attn W. Hardwick, M/S 31
1500 Garden of the Gods Road
Colorado Springs, CO 80907

Kaman Tempo
Attn DASIAC
PO Drawer QQ
Santa Barbara, CA 93102

Mission Research
Attn D. Alexander
1720 Randolph Road
Albuquerque, NM 87104

Mission Research
Attn P. Reiner
4935 N 30th Street
Colorado Springs, CO 80919-3156

Physics International
Attn C. Gilman
Attn S. Wong
2700 Merced Street, PO Box 1538
San Leandro, CA 94577

Physitron, Inc.
Attn D. Sapach
Attn G. Grant
Attn J. Harper
Attn J. Sheehy
Attn M. Christopher
Attn P. Jessen
Attn R. Skarupa
Attn T. Henderson
3325 Triana Blvd., Suite A
Huntsville, AL 35805

Physitron, Inc.
Attn J. Azarewicz
Attn M. Rose
P.O. Box 27627
San Diego, CA 92128-0950

SAIC
Attn J. Tigner
1710 Goodridge Drive
McLean, VA 22102

SAIC, Inc.
Attn K. Sites
3353 S. Highland Drive, Suite 206
Las Vegas, NV 89109

SAIC, Tower II
Attn R. Sutton
PO Box 1303
McLean, VA 22102

Teledyne Brown Engineering
Attn R. DeKalb/MS 50
Cummings Research Park
Huntsville, AL 35807

W. J. Schafer Associates
Attn E. Alcaraz
1901 N. Ft. Meyer Drive, Suite 800
Arlington, VA 22209

US Army Laboratory Command
Attn AMSLC-DL, R. Vitali

Installation Support Activity
Attn SLCIS-CC, COL W. Whitten

USAISC
Attn AMSLC-IM-VA, Admin Ser Br
Attn AMSLC-IM-VP, Tech Pub Br (2 copies)

Harry Diamond Laboratories
Attn SLCHD-TL, Library (3 copies)
Attn SLCHD-TL, Library (WRF)
Attn SLCHD-CS, J. Sattler
Attn SLCHD-D, J. Reed
Attn SLCHD-D, R. Gilbert
Attn SLCHD-DD, J. Scully
Attn SLCHD-HPM, J. Agee

Distribution (cont'd)

Harry Diamond Laboratories (cont'd)

Attn SLCHD-NW, W. Vault
Attn SLCHD-NW-E, J. Ingram
Attn SLCHD-NW-HPM, S. Graybill
Attn SLCHD-NW-P, D. Davis
Attn SLCHD-NW-P, J. Gwaltney
Attn SLCHD-NW-P, T. Flory
Attn SLCHD-NW-RP, J. McGarrity
Attn SLCHD-NW-RP, T. Oldham
Attn SLCHD-NW-RS, A. Bromborsky
Attn SLCHD-NW-RS, A. Kehs
Attn SLCHD-NW-RS, A. Mark
Attn SLCHD-NW-RS, A. Poirier
Attn SLCHD-NW-RS, C. Casaer
Attn SLCHD-NW-RS, C. Lazard
Attn SLCHD-NW-RS, D. Weidenheimer
Attn SLCHD-NW-RS, G. Huttlin
Attn SLCHD-NW-RS, J. Deaver
Attn SLCHD-NW-RS, J. Corrigan
Attn SLCHD-NW-RS, K. Kerris
Attn SLCHD-NW-RS, M. Caruso
Attn SLCHD-NW-RS, M. Litz (10 copies)

Harry Diamond Laboratories (cont'd)

Attn SLCHD-NW-RS, O. Benton
Attn SLCHD-NW-RS, W. Lilley
Attn SLCHD-TA, R. Sebol
Attn SLCHD-NW-TN, A. Baba
Attn SLCHD-NW-TN, S. Share
Attn SLCHD-NW-TS, C. Self
Attn SLCHD-NW-TS, C. Tipton
Attn SLCHD-NW-TS, D. Robertson
(20 copies)
Attn SLCHD-NW-TS, G. Ferguson
Attn SLCHD-NW-TS, G. Ovrebo
Attn SLCHD-NW-TS, H. Eisen
Attn SLCHD-NW-TS, J. Blackburn
(25 copies)
Attn SLCHD-NW-TS, J. Halpin
Attn SLCHD-NW-TS, J. Vanderwall
Attn SLCHD-NW-TS, L. Faustini
Attn SLCHD-NW-TS, M. Bumbaugh
Attn SLCHD-NW-TS, S. Blomquist
Attn SLCHD-NW-TS, S. Murrill
Attn SLCHD-NW-TS, S. Scozzie